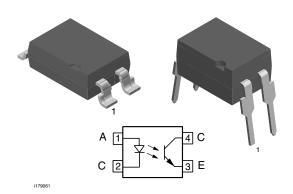


Optocoupler, Phototransistor Output, Low Input Current

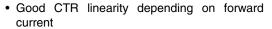


DESCRIPTION

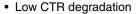
The SFH618A (DIP) and SFH6186 (SMD) feature a high current transfer ratio, low coupling capacitance and high isolation voltage. These couplers have a GaAs infrared diode emitter, which is optically coupled to silicon planar phototransistor detector, and is incorporated in a plastic DIP-4 or SMD package.

The coupling devices are designed for signal transmission between two electrically separated circuits. The couplers are end-stackable with 2.54 mm lead spacing. Creepage and clearance distances of > 8.0 mm achieved with option 6. This version complies with IEC 60950 (DIN VDE 0805) for reinforced insulation to an operation voltage of 400 V_{RMS} or DC.

FEATURES







- High collector emitter voltage, V_{CEO} = 55 V
- Isolation test voltage, 5300 V_{RMS}
 - V_{RMS}
- · Low coupling capacitance
- End stackable, 0.100" (2.54 mm) spacing
- · High common mode transient immunity
- Lead (Pb)-free component
- Component in accordance to RoHS 2002/95/EC and WEEE 2002/96/EC

APPLICATIONS

- Telecom
- · Industrial controls
- Battery powered equipment
- · Office machines

AGENCY APPROVALS

- UL1577, file no. E52744 system code H or J, double protection
- CSA 93751
- DIN EN 60747-5-5 (VDE 0884) available with option 1
- BSI IEC 60950; IEC 60065
- FIMKO

ORDER INFORMATION					
PART	REMARKS				
SFH618A-2	CTR 63 % to 125 %, DIP-4				
SFH618A-3	CTR 100 % to 200 %, DIP-4				
SFH618A-4	CTR 160 % to 320 %, DIP-4				
SFH618A-5	CTR 250 % to 500 %, DIP-4				
SFH6186-2	CTR 63 % to 125 %, SMD-4				
SFH6186-3	CTR 100 % to 200 %, SMD-4				
SFH6186-4	CTR 160 % to 320 %, SMD-4				
SFH6186-5	CTR 250 % to 500 %, SMD-4				
SFH618A-3X006	CTR 100 % to 200 %, DIP-4 400 mil (option 6)				
SFH618A-3X007	CTR 100 % to 200 %, SMD-4 (option 7)				
SFH618A-4X006	CTR 160 % to 320 %, DIP-4 400 mil (option 6)				
SFH618A-5X006	CTR 250 % to 500 %, DIP-4 400 mil (option 6)				
SFH618A-5X007	CTR 250 % to 500 %, SMD-4 (option 7)				

Note

For additional information on the available options refer to option information.

Optocoupler, Phototransistor Output, Low Input Current



ABSOLUTE MAXIMUM I	RATINGS ⁽¹⁾			
PARAMETER	TEST CONDITION	SYMBOL	VALUE	UNIT
INPUT	·			
Reverse voltage		V _R	6	V
Power dissipation		P _{diss}		mW
Forward current		I _F	60	mA
OUTPUT				
Collector emitter voltage		V _{CE}	55	V
Emitter collector voltage		V _{EC}	7	V
Collector current		Ic	50	mA
Collector current	$t_p \le 1.0 \text{ ms}$	I _C	100	mA
Power dissipation		P_{diss}	150	mW
COUPLER				
Isolation test voltage between emitter and detector		V_{ISO}	5300	V_{RMS}
Isolation resistance	V _{IO} = 500 V, T _{amb} = 25 °C	R _{IO}	≥ 10 ¹²	Ω
Isolation resistance	V _{IO} = 500 V, T _{amb} = 100 °C	R _{IO}	≥ 10 ¹¹	Ω
Storage temperature range		T _{stg}	- 55 to + 150	°C
Ambient temperature range		T _{amb}	- 55 to + 100	°C
Junction temperature		T _j	100	°C
Soldering temperature (2)	max. 10 s, dip soldering distance to seating plane ≥ 1.5 mm	T _{sld}	260	°C

Notes

Stresses in excess of the absolute maximum ratings can cause permanent damage to the device. Functional operation of the device is not implied at these or any other conditions in excess of those given in the operational sections of this document. Exposure to absolute maximum ratings for extended periods of the time can adversely affect reliability.

(2) Refer to reflow profile for soldering conditions for surface mounted devices (SMD). Refer to wave profile for soldering conditions for through hole devices (DIP).

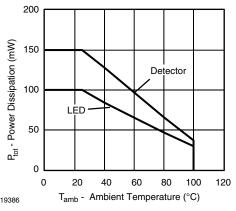


Fig. 1 - Permissible Power Dissipation vs. Ambient Temperature

ELECTRICAL CHARACTERISTICS								
PARAMETER	TEST CONDITION	PART	SYMBOL	MIN.	TYP.	MAX.	UNIT	
INPUT	INPUT							
Forward voltage	$I_F = 5 \text{ mA}$		V_{F}		1.1	1.5	V	
Reverse current	V _R = 6 V		I _R		0.01	10	μΑ	
Capacitance	V _R = 0 V, f = 1 MHz		Co		25		pF	
Thermal resistance			R _{thja}		1070		K/W	

 $^{^{(1)}}$ $T_{amb} = 25$ °C, unless otherwise specified.



Vishay Semiconductors Optocoupler, Phototransistor Output, Low Input Current

PARAMETER	TEST CONDITION	PART	SYMBOL	MIN.	TYP.	MAX.	UNIT
OUTPUT	TEST CONDITION	I AILI	OTWIDOL	IVIII 4.		IVIAA.	Oitii
Collector emitter leakage current	V _{CE} = 10 V		I _{CEO}		10	200	nA
Collector emitter capacitance	V _{CE} = 5 V, f = 1 MHz		C _{CE}		7		pF
Thermal resistance			R _{thja}		500		K/W
COUPLER							
	I _C = 0.32 mA, I _F = 1 mA	SFH618A-2	V _{CEsat}		0.25	0.4	V
		SFH6186-2	V _{CEsat}		0.25	0.4	V
Collector emitter esturation voltage	I _C = 0.5 mA, I _F = 1 mA	SFH618A-3	V _{CEsat}		0.25	0.4	V
		SFH6186-3	V _{CEsat}		0.25	0.4	V
Collector emitter saturation voltage	I _C = 0.8 mA, I _F = 1 mA	SFH618A-4	V _{CEsat}		0.25	0.4	V
		SFH6186-4	V _{CEsat}		0.25	0.4	V
	_ 1 05 m	SFH618A-5	V _{CEsat}		0.25	0.4	V
	$I_C = 1.25 \text{ mA}, I_F = 1 \text{ mA}$	SFH6186-5	V _{CEsat}		0.25	0.4	V
Coupling capacitance			C _C		0.25		pF

Note

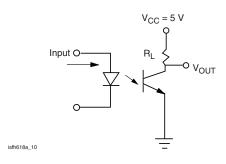
 $T_{amb} = 25$ °C, unless otherwise specified. Minimum and maximum values are testing requirements. Typical values are characteristics of the device and are the result of engineering evaluation. Typical values are for information only and are not part of the testing requirements.

CURRENT TRANSFER RATIO								
PARAMETER	TEST CONDITION	PART	SYMBOL	MIN.	TYP.	MAX.	UNIT	
	I _E = 1 mA, V _{CE} = 0.5 V	SFH618A-2	CTR	63		125	%	
	IF = 1 IIIA, VCE = 0.5 V	SFH6186-2	CTR	63		125	%	
	I _E = 0.5 mA, V _{CE} = 1.5 V	SFH618A-2	CTR	32	75		%	
	I _F = 0.5 IIIA, V _{CE} = 1.5 V	SFH6186-2	CTR	32	75		%	
	I _E = 1 mA, V _{CE} = 0.5 V	SFH618A-3	CTR	100		200	%	
	IF = 1 IIIA, VCE = 0.5 V	SFH6186-3	CTR	100		200	%	
	I _F = 0.5 mA, V _{CE} = 1.5 V	SFH618A-3	CTR	50	120		%	
		SFH6186-3	CTR	50	120		%	
I _C /I _F	I _E = 1 mA, V _{CE} = 0.5 V	SFH618A-4	CTR	160		320	%	
	IF = 1 IIIA, VCE = 0.5 V	SFH6186-4	CTR	160		320	%	
	I _E = 0.5 mA, V _{CE} = 1.5 V	SFH618A-4	CTR	80	200		%	
	IF = 0.5 IIIA, VCE = 1.5 V	SFH6186-4	CTR	80	200		%	
	I _E = 1 mA, V _{CE} = 0.5 V	SFH618A-5	CTR	250		500	%	
	IF = 1 IIIA, VCE = 0.5 V	SFH6186-5	CTR	250		500	%	
	I _E = 0.5 mA, V _{CE} = 1.5 V	SFH618A-5	CTR	125	300		%	
	IF = 0.5 IIIA, VCE = 1.5 V	SFH6186-5	CTR	125	300		%	

SWITCHING CHARACTERISTICS								
PARAMETER	TEST CONDITION	SYMBOL	MIN.	TYP.	MAX.	UNIT		
Turn on time	V_{CC} = 5 V, I_C = 2 mA, R_L = 100 Ω	t _{on}		6		μs		
Rise time	V_{CC} = 5 V, I_C = 2 mA, R_L = 100 Ω	t _r		3.5		μs		
Turn off time	V_{CC} = 5 V, I_C = 2 mA, R_L = 100 Ω	t _{off}		5.5		μs		
Fall time	$V_{CC} = 5 \text{ V}, I_C = 2 \text{ mA}, R_L = 100 \Omega$	t _f		5		μs		

Optocoupler, Phototransistor Output, Low Input Current





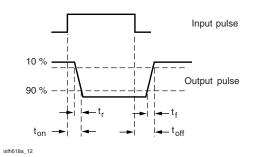


Fig. 2 - Test Circuit

Fig. 3 - Test Circuit and Waveforms

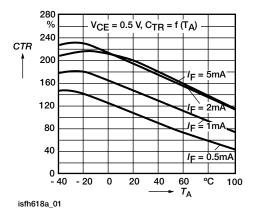
SAFETY AND INSULATION RATINGS								
PARAMETER	TEST CONDITION	SYMBOL	MIN.	TYP.	MAX.	UNIT		
Climatic classification (according to IEC 68 part 1)				55/100/21				
Comparative tracking index		CTI	175		399			
V _{IOTM}			10000			V		
V _{IORM}			890			V		
P _{SO}					400	mW		
I _{SI}					275	mA		
T _{SI}					175	°C		
Creepage distance	standard DIP-4		7			mm		
Clearance distance	standard DIP-4		7			mm		
Creepage distance	400 mil DIP-4		8			mm		
Clearance distance	400 mil DIP-4		8			mm		
Insulation thickness, reinforced rated	per IEC 60950 2.10.5.1		0.4			mm		

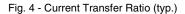
Note

As per IEC 60747-5-2, § 7.4.3.8.1, this optocoupler is suitable for "safe electrical insulation" only within the safety ratings. Compliance with the safety ratings shall be ensured by means of protective circuits.

TYPICAL CHARACTERISTICS

T_{amb} = 25 °C, unless otherwise specified





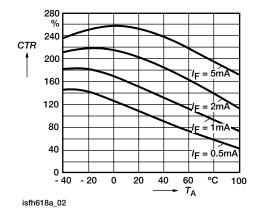


Fig. 5 - Current Transfer Ratio (typ.)



Optocoupler, Phototransistor Output, Low Input Current

Vishay Semiconductors

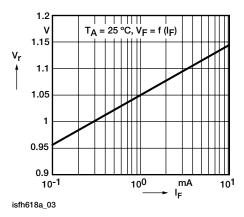


Fig. 6 - Diode Forward Voltage (typ.)

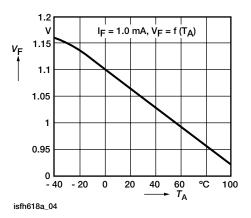


Fig. 7 - Diode Forward Voltage (typ.)

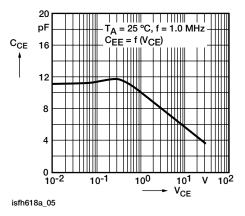


Fig. 8 - Transistor Capacitance

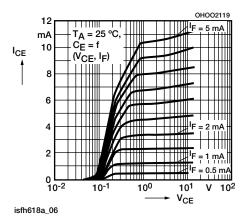


Fig. 9 - Output Characteristics

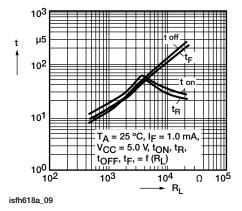
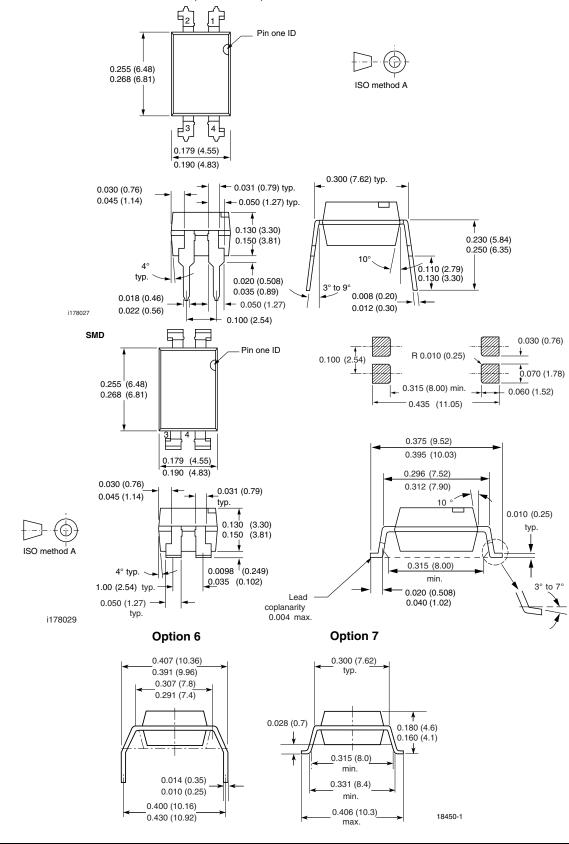


Fig. 10 - Switching Times (typ.)

Optocoupler, Phototransistor Output, Low Input Current



PACKAGE DIMENSIONS in inches (millimeters)





Optocoupler, Phototransistor Output, Low Input Current

Vishay Semiconductors

OZONE DEPLETING SUBSTANCES POLICY STATEMENT

It is the policy of Vishay Semiconductor GmbH to

- 1. Meet all present and future national and international statutory requirements.
- 2. Regularly and continuously improve the performance of our products, processes, distribution and operating systems with respect to their impact on the health and safety of our employees and the public, as well as their impact on the environment.

It is particular concern to control or eliminate releases of those substances into the atmosphere which are known as ozone depleting substances (ODSs).

The Montreal Protocol (1987) and its London Amendments (1990) intend to severely restrict the use of ODSs and forbid their use within the next ten years. Various national and international initiatives are pressing for an earlier ban on these substances.

Vishay Semiconductor GmbH has been able to use its policy of continuous improvements to eliminate the use of ODSs listed in the following documents.

- 1. Annex A, B and list of transitional substances of the Montreal Protocol and the London Amendments respectively.
- Class I and II ozone depleting substances in the Clean Air Act Amendments of 1990 by the Environmental Protection Agency (EPA) in the USA.
- 3. Council Decision 88/540/EEC and 91/690/EEC Annex A, B and C (transitional substances) respectively.

Vishay Semiconductor GmbH can certify that our semiconductors are not manufactured with ozone depleting substances and do not contain such substances.

We reserve the right to make changes to improve technical design and may do so without further notice.

Parameters can vary in different applications. All operating parameters must be validated for each customer application by the customer. Should the buyer use Vishay Semiconductors products for any unintended or unauthorized application, the buyer shall indemnify Vishay Semiconductors against all claims, costs, damages, and expenses, arising out of, directly or indirectly, any claim of personal damage, injury or death associated with such unintended or unauthorized use.

Vishay Semiconductor GmbH, P.O.B. 3535, D-74025 Heilbronn, Germany

Document Number: 83673 Rev. 1.9, 10-Dec-08



Vishay

Disclaimer

All product specifications and data are subject to change without notice.

Vishay Intertechnology, Inc., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Vishay"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained herein or in any other disclosure relating to any product.

Vishay disclaims any and all liability arising out of the use or application of any product described herein or of any information provided herein to the maximum extent permitted by law. The product specifications do not expand or otherwise modify Vishay's terms and conditions of purchase, including but not limited to the warranty expressed therein, which apply to these products.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Vishay.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications unless otherwise expressly indicated. Customers using or selling Vishay products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify Vishay for any damages arising or resulting from such use or sale. Please contact authorized Vishay personnel to obtain written terms and conditions regarding products designed for such applications.

Product names and markings noted herein may be trademarks of their respective owners.

Document Number: 91000 Revision: 18-Jul-08